

# Contents

Preface to the Second Edition	xxiii
Preface to the First Edition	xxvii
Gallery	xxxiii
<b>Chapter 1: Overview</b>	<b>1</b>
1.1 The scanning tunneling microscope . . . . .	1
1.2 The concept of tunneling . . . . .	3
1.2.1 Transmission coefficient . . . . .	3
1.2.2 Semiclassical approximation . . . . .	6
1.2.3 The Landauer theory . . . . .	6
1.2.4 Tunneling conductance . . . . .	10
1.3 Probing electronic structure at atomic scale . . . . .	12
1.3.1 Experimental observations . . . . .	15
1.3.2 Origin of atomic resolution in STM . . . . .	18
1.4 The atomic force microscope . . . . .	21
1.4.1 Atomic-scale imaging by AFM . . . . .	21
1.4.2 Role of covalent bonding in AFM imaging . . . . .	24
1.5 Illustrative applications . . . . .	25
1.5.1 Catalysis research . . . . .	25
1.5.2 Atomic-scale imaging at the liquid-solid interface . . . . .	29
1.5.3 Atom manipulation . . . . .	33
1.5.4 Imaging and manipulating DNA using AFM . . . . .	35
<b>Part I Principles</b>	<b>41</b>
<b>Chapter 2: Tunneling Phenomenon</b>	<b>45</b>
2.1 The metal–insulator–metal tunneling junction . . . . .	46
2.2 The Bardeen theory of tunneling . . . . .	48
2.2.1 One-dimensional case . . . . .	48
2.2.2 Tunneling spectroscopy . . . . .	52
2.2.3 Energy dependence of tunneling matrix elements . . . . .	53
2.2.4 Asymmetry in tunneling spectrum . . . . .	54
2.2.5 Three-dimensional case . . . . .	57
2.2.6 Error estimation . . . . .	59
2.2.7 Wavefunction correction . . . . .	60
2.2.8 The transfer-Hamiltonian formalism . . . . .	61
2.2.9 The tunneling matrix . . . . .	63

2.2.10 Relation to the Landauer theory . . . . .	64
<b>2.3 Inelastic tunneling . . . . .</b>	<b>64</b>
2.3.1 Experimental facts . . . . .	65
2.3.2 Frequency condition . . . . .	66
2.3.3 Effect of finite temperature . . . . .	67
<b>2.4 Spin-polarized tunneling . . . . .</b>	<b>69</b>
2.4.1 General formalism . . . . .	70
2.4.2 The spin-valve effect . . . . .	72
2.4.3 Experimental observations . . . . .	76
<b>Chapter 3: Tunneling Matrix Elements</b>	<b>77</b>
3.1 Introduction . . . . .	77
3.2 Tip wavefunctions . . . . .	78
3.2.1 General form . . . . .	78
3.2.2 Tip wavefunctions as Green's functions . . . . .	81
3.3 The derivative rule: individual cases . . . . .	82
3.3.1 $s$ -wave tip state . . . . .	82
3.3.2 $p$ -wave tip states . . . . .	83
3.3.3 $d$ -wave tip states . . . . .	84
3.3.4 Complex tip states . . . . .	84
3.4 The derivative rule: general case . . . . .	85
3.5 An intuitive interpretation . . . . .	91
<b>Chapter 4: Atomic Forces</b>	<b>93</b>
4.1 Van der Waals force . . . . .	93
4.1.1 The van der Waals equation of state . . . . .	93
4.1.2 The origin of van der Waals force . . . . .	94
4.1.3 Van der Waals force between a tip and a sample . . . . .	96
4.2 Hard-core repulsion . . . . .	98
4.3 The ionic bond . . . . .	98
4.4 The covalent bond: The concept . . . . .	100
4.4.1 Heisenberg's model of resonance . . . . .	101
4.4.2 The hydrogen molecule-ion . . . . .	104
4.4.3 Three regimes of interaction . . . . .	105
4.4.4 Van der Waals force . . . . .	106
4.4.5 Resonance energy as tunneling matrix element . . . . .	107
4.4.6 Evaluation of the modified Bardeen integral . . . . .	111
4.4.7 Repulsive force . . . . .	114
4.5 The covalent bond: Many-electron atoms . . . . .	115

4.5.1	The homonuclear diatomic molecules . . . . .	115
4.5.2	The perturbation approach . . . . .	115
4.5.3	Evaluation of the Bardeen Integral . . . . .	118
4.5.4	Comparison with experimental data . . . . .	119

## **Chapter 5: Atomic Forces and Tunneling** 123

5.1	The principle of equivalence . . . . .	123
5.2	General theory . . . . .	126
5.2.1	The double-well problem . . . . .	126
5.2.2	Canonical transformation of the transfer Hamiltonian	128
5.2.3	Diagonizing the tunneling matrix . . . . .	130
5.3	Case of a metal tip and a metal sample . . . . .	131
5.3.1	Van der Waals force . . . . .	132
5.3.2	Resonance energy between two metal electrodes . . . . .	132
5.3.3	A measurable consequence . . . . .	135
5.3.4	Repulsive force . . . . .	136
5.4	Experimental verifications . . . . .	136
5.4.1	An early experiment . . . . .	136
5.4.2	Experiments with frequency-modulation AFM . . . . .	138
5.4.3	Experiments with static AFM . . . . .	140
5.4.4	Non-contact atomic force spectroscopy . . . . .	143
5.5	Threshold resistance in atom manipulation . . . . .	145

## **Chapter 6: Nanometer-Scale Imaging** 149

6.1	Types of STM and AFM images . . . . .	149
6.2	The Tersoff–Hamann model . . . . .	151
6.2.1	The concept . . . . .	151
6.2.2	The original derivation . . . . .	152
6.2.3	Profiles of surface reconstructions . . . . .	155
6.2.4	Extension to finite bias voltages . . . . .	158
6.2.5	Surface states: the concept . . . . .	160
6.2.6	Surface states: STM observations . . . . .	162
6.2.7	Heterogeneous surfaces . . . . .	166
6.3	Limitations of the Tersoff–Hamann model . . . . .	166

## **Chapter 7: Atomic-Scale Imaging** 169

7.1	Experimental facts . . . . .	170
7.1.1	Universality of atomic resolution . . . . .	170
7.1.2	Corrugation inversion . . . . .	170
7.1.3	Tip-state dependence . . . . .	171

7.1.4	Distance dependence of corrugation . . . . .	173
7.2	Intuitive explanations . . . . .	174
7.2.1	Sharpness of tip states . . . . .	174
7.2.2	Phase effect . . . . .	175
7.2.3	Arguments based on the reciprocity principle . . . . .	177
7.3	Analytic treatments . . . . .	178
7.3.1	A one-dimensional case . . . . .	178
7.3.2	Surfaces with hexagonal symmetry . . . . .	182
7.3.3	Corrugation inversion . . . . .	186
7.3.4	Profiles of atomic states as seen by STM . . . . .	190
7.3.5	Independent-orbital approximation . . . . .	194
7.4	First-principles studies: tip electronic states . . . . .	198
7.4.1	W clusters as STM tip models . . . . .	198
7.4.2	Density-functional study of a W–Cu STM junction .	199
7.4.3	Transition-metal pyramidal tips . . . . .	199
7.4.4	Transition-metal atoms adsorbed on W slabs . . . . .	200
7.5	First-principles studies: the images . . . . .	202
7.5.1	Transition-metal surfaces . . . . .	202
7.5.2	Atomic corrugation and surface waves . . . . .	204
7.5.3	Atom-resolved AFM images . . . . .	205
7.6	Spin-polarized STM . . . . .	209
7.7	Chemical identification of surface atoms . . . . .	212
7.8	The principle of reciprocity . . . . .	214
<b>Chapter 8: Nanomechanical Effects</b>		<b>219</b>
8.1	Mechanical stability of the tip–sample junction . . . . .	220
8.1.1	Experimental observations . . . . .	220
8.1.2	Condition of mechanical stability . . . . .	223
8.1.3	Relaxation and the apparent $G \sim z$ relation . . . . .	229
8.2	Mechanical effects on observed corrugations . . . . .	231
8.2.1	Soft surfaces . . . . .	231
8.2.2	Hard surfaces . . . . .	233
8.2.3	First-principles simulations . . . . .	236
8.2.4	Advanced topics . . . . .	237
8.2.5	The Pethica mechanism . . . . .	238
8.3	Force in tunneling-barrier measurements . . . . .	238

**Chapter 9: Piezoelectric Scanner**

245

9.1	Piezoelectricity . . . . .	245
9.1.1	Piezoelectric effect . . . . .	245
9.1.2	Inverse piezoelectric effect . . . . .	246
9.2	Piezoelectric materials in STM and AFM . . . . .	249
9.2.1	Quartz . . . . .	249
9.2.2	Lead zirconate titanate ceramics . . . . .	250
9.3	Piezoelectric devices in STM and AFM . . . . .	254
9.3.1	Tripod scanner . . . . .	254
9.3.2	Bimorph . . . . .	255
9.4	The tube scanner . . . . .	257
9.4.1	Deflection . . . . .	258
9.4.2	In situ testing and calibration . . . . .	260
9.4.3	Resonant frequencies . . . . .	263
9.4.4	Tilt compensation: the s-scanner . . . . .	264
9.4.5	Repolarizing a depolarized tube piezo . . . . .	265
9.5	The shear piezo . . . . .	265

**Chapter 10: Vibration Isolation**

269

10.1	Basic concepts . . . . .	269
10.2	Environmental vibration . . . . .	273
10.2.1	Measurement method . . . . .	274
10.2.2	Vibration isolation of the foundation . . . . .	275
10.3	Vibrational immunity of STM . . . . .	277
10.4	Suspension-spring systems . . . . .	278
10.4.1	Analysis of two-stage systems . . . . .	278
10.4.2	Choice of springs . . . . .	280
10.4.3	Eddy-current damper . . . . .	281
10.5	Pneumatic systems . . . . .	282

**Chapter 11: Electronics and Control**

283

11.1	Current amplifier . . . . .	283
11.1.1	Johnson noise and shot noise . . . . .	284
11.1.2	Frequency response . . . . .	286
11.1.3	Microphone effect . . . . .	287
11.1.4	Logarithmic amplifier . . . . .	288
11.2	Feedback circuit . . . . .	289

11.2.1 Steady-state response . . . . .	290
11.2.2 Transient response . . . . .	292
11.3 Computer interface . . . . .	297
11.3.1 Automatic approaching . . . . .	298
<b>Chapter 12: Mechanical design</b>	<b>299</b>
12.1 The louse . . . . .	299
12.2 The pocket-size STM . . . . .	300
12.3 The single-tube STM . . . . .	301
12.4 The Besocke-type STM: the beetle . . . . .	302
12.5 The walker . . . . .	305
12.6 The kangaroo . . . . .	306
12.7 The Inchworm . . . . .	308
12.8 The match . . . . .	309
<b>Chapter 13: Tip Treatment</b>	<b>313</b>
13.1 Introduction . . . . .	313
13.2 Electrochemical tip etching . . . . .	314
13.3 Ex situ tip treatments . . . . .	317
13.3.1 Annealing . . . . .	317
13.3.2 Field evaporation and controlled deposition . . . . .	318
13.3.3 Annealing with a field . . . . .	319
13.3.4 Atomic metallic ion emission . . . . .	320
13.3.5 Field-assisted reaction with nitrogen . . . . .	322
13.4 In situ tip treatments . . . . .	324
13.4.1 High-field treatment . . . . .	324
13.4.2 Controlled collision . . . . .	325
13.5 Tip treatment for spin-polarized STM . . . . .	326
13.5.1 Coating the tip with ferromagnetic materials . . . . .	326
13.5.2 Coating the tip with antiferromagnetic materials . . . . .	327
13.5.3 Controlled collision with magnetic surfaces . . . . .	327
13.6 Tip preparation for electrochemistry STM . . . . .	328
<b>Chapter 14: Scanning Tunneling Spectroscopy</b>	<b>331</b>
14.1 Electronics for scanning tunneling spectroscopy . . . . .	331
14.2 Nature of the observed tunneling spectra . . . . .	332
14.3 Tip treatment for spectroscopy studies . . . . .	334

14.3.1 Annealing . . . . .	334
14.3.2 Controlled collision with a metal surface . . . . .	336
14.4 The Feenstra parameter . . . . .	337
14.5 Determination of the tip DOS . . . . .	338
14.5.1 Ex situ methods . . . . .	338
14.5.2 In situ methods . . . . .	340
14.6 Inelastic scanning tunneling spectroscopy . . . . .	344
14.6.1 Instrumentation . . . . .	344
14.6.2 Effect of finite modulation voltage . . . . .	345
14.6.3 Experimental observations . . . . .	347
<b>Chapter 15: Atomic Force Microscopy</b>	<b>349</b>
15.1 Static mode and dynamic mode . . . . .	350
15.2 The cantilever . . . . .	351
15.2.1 Basic requirements . . . . .	351
15.2.2 Fabrication . . . . .	352
15.3 Static force detection . . . . .	354
15.3.1 Optical beam deflection . . . . .	354
15.3.2 Optical interferometry . . . . .	356
15.4 Tapping-mode AFM . . . . .	357
15.4.1 Acoustic actuation in liquids . . . . .	358
15.4.2 Magnetic actuation in liquids . . . . .	359
15.5 Non-contact AFM . . . . .	361
15.5.1 Case of small amplitude . . . . .	361
15.5.2 Case of finite amplitude . . . . .	364
15.5.3 Response function for frequency shift . . . . .	365
15.5.4 Second harmonics . . . . .	366
15.5.5 Average tunneling current . . . . .	368
15.5.6 Implementation . . . . .	369
<b>Appendix A: Green's Functions</b>	<b>371</b>
<b>Appendix B: Real Spherical Harmonics</b>	<b>373</b>
<b>Appendix C: Spherical Modified Bessel Functions</b>	<b>377</b>
<b>Appendix D: Plane Groups and Invariant Functions</b>	<b>381</b>
D.1 A brief summary of plane groups . . . . .	382
D.2 Invariant functions . . . . .	385

## **Appendix E: Elementary Elasticity Theory** 389

E.1	Stress and strain . . . . .	389
E.2	Small deflection of beams . . . . .	391
E.3	Vibration of beams . . . . .	394
E.4	Torsion . . . . .	395
E.5	Helical springs . . . . .	397
E.6	Contact stress: The Hertz formulas . . . . .	398